TEST REPORT

FCC ID: U8O-OBC5-LTE Product: Micronet SmartHub LTE Model No.: Micronet SmartHub Additional Model No.: N/A Trade Mark: Micronet Report No.: TCT180806E042 Issued Date: Sep. 06, 2018

Issued for:

Micronet 1865 West 2100 South, Suite 2, Salt Lake City, Utah, 84119 United States

Issued By:

Shenzhen Tongce Testing Lab. 1B/F., Building 1, Yibaolai Industrial Park, Qiaotou, Fuyong, Baoan District, Shenzhen, Guangdong, China TEL: +86-755-27673339

FAX: +86-755-27673332

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TCT 通测检测 TESTING CENTRE TECHNOLOGY

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通测检测 TESTING CENTRE TECHNOLOGY **Test Certification**

Product:	Micronet SmartHub LTE
Model No.:	Micronet SmartHub
Additional Model:	N/A
Trade Mark:	Micronet
Applicant:	Micronet
Address:	1865 West 2100 South, Suite 2, Salt Lake City, Utah, 84119 United States
Manufacturer:	Micronet
Address:	1865 West 2100 South, Suite 2, Salt Lake City, Utah, 84119 United States
Date of Test:	Aug. 07, 2018 - Sep. 05, 2018
Applicable Standards:	FCC CFR Title 47 Part 2 FCC CFR Title 47 Part22 FCC CFR Title 47 Part24 FCC CFR Title 47 Part27

The above equipment has been tested by Shenzhen Tongce Testing Lab. and found compliance with the requirements set forth in the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Tested By: Jin Wang

Reviewed By:

Beryl Zhao

msm

Approved By:

Tomsin

Date: Sep. 05, 2018 Date: Sep. 06, 2018 Date: Sep. 06, 2018

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Hotline: 400-6611-140 Tel: 86-755-27673339 http://www.tct-lab.com Fax: 86-755-27673332

Requirement	CFR 47 Section	Result
Conducted Output Power	§2.1046; §22.913; §24.232(c); §27.50(d); §27.50(c); §27.50(b);	PASS
Peak-to-Average Ratio	§2.1046; §24.232(d) §27.50(d); §27.50(c); §27.50(b);	PASS
Effective Radiated Power	§2.1046; §22.913; §24.232(c); §27.50(d); §27.50(c); §27.50(b);	PASS
Equivalent Isotropic Radiated Power	§2.1046; §22.913; §24.232(c); §27.50(d); §27.50(c); §27.50(b);	PASS
Occupied Bandwidth	§2.1049; §24.238(b); §27.53;	PASS
Band Edge	§2.1051; §22.917(a); §27.53(h); §27.53(c); §27.53(g); §24.238(a);	PASS
Conducted Spurious Emission	§2.1051; §22.917(a); §27.53(h); §27.53(g); §27.53(c); §24.238(a);	PASS
Field Strength of Spurious Radiation	§2.1053; §22.917(a); §27.53(g) ; §27.53(c); §27.53(h); §24.238(a);	PASS
Frequency Stability for Temperature & Voltage	§2.1055;§22.355; §27.54; §24.235;	PASS

Note:

1. PASS: Test item meets the requirement.

2. Fail: Test item does not meet the requirement.

1.8

3. N/A: Test case does not apply to the test object.

4. The test result judgment is decided by the limit of test standard.

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3. EUT Description

Product:	Micronet SmartHub LTE
Model No.:	Micronet SmartHub
Additional Model:	N/A
Trade Mark:	Micronet
Hardware Version:	P1
Software Version:	0.1.8.0
Tx Frequency:	LTE Band 2: 1850 MHz ~ 1910 MHz LTE Band 4: 1710 MHz ~ 1755 MHz LTE Band 5: 824 MHz ~ 849 MHz LTE Band 12: 699 MHz ~ 716 MHz LTE Band 17: 704 MHz ~ 716 MHz
Rx Frequency:	LTE Band 2: 1930MHz ~ 1990 MHz LTE Band 4: 2110 MHz ~ 2155 MHz LTE Band 5: 869 MHz ~ 894 MHz LTE Band 12: 729 MHz ~ 746 MHz LTE Band 17: 734 MHz ~ 746 MHz
Bandwidth:	LTE Band 2: 1.4MHz /3MHz /5MHz /10MHz /15MHz / 20MHz LTE Band 4: 1.4MHz /3MHz /5MHz /10MHz /15MHz / 20MHz LTE Band 5: 1.4MHz /3MHz /5MHz /10MHz LTE Band 12: 1.4MHz /3MHz /5MHz /10MHz LTE Band 17: 5MHz /10MHz
Maximum Output Power to Antenna:	LTE Band 2: 23.49dBm LTE Band 4: 23.33dBm LTE Band 5: 23.53dBm LTE Band 12: 23.21dBm LTE Band 17: 25.01dBm
99% Occupied Bandwidth:	LTE Band 2: 17M9G7D LTE Band 4: 17M9G7D LTE Band 5: 8M95G7D LTE Band 12: 8M98W7D LTE Band 17: 8M98W7D
Type of Modulation:	QPSK / 16QAM
Antenna Type:	Internal Antenna
Antenna Gain:	LTE Band 2: 1.9dBi LTE Band 4: 1.9dBi LTE Band 5: 1.9dBi LTE Band 12: 1.9dBi LTE Band 17: 1.9dBi
Power Supply:	DC 12/24V

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Emission Designator

LTE Band 2	Band 2 QPSK		16QAM	
BW(MHz)	Emission Designator (99%OBW)	Maximum EIRP(W)	Emission Designator (99%OBW)	Maximum EIRP(W)
1.4	1M08G7D	0.311	1M08W7D	0.272
3	2M69G7D	0.317	2M69W7D	0.275
5	4M48G7D	0.333	4M49W7D	0.280
10	8M96G7D	0.341	8M95W7D	0.288
15	13M4G7D	0.333	13M4W7D	0.284
20	17M9G7D	0.346	17M9W7D	0.281
LTE Band 4	QPSK		160	QAM

LTE Band 4	(QPSK	16QAM	
BW(MHz)	Emission Designator (99%OBW)	Maximum EIRP(W)	Emission Designator (99%OBW)	Maximum EIRP(W)
1.4	1M08G7D	0.311	1M08W7D	0.254
3	2M69G7D	0.307	2M69W7D	0.261
5	4M48G7D	0.327	4M49W7D	0.274
10	8M96G7D	0.313	8M95W7D	0.270
15	13M4G7D	0.311	13M4W7D	0.262
20	17M9G7D	0.333	17M9W7D	0.242

LTE Band 5	nd 5 QPSK 16QAM			6QAM
BW(MHz)	Emission Designator (99%OBW)	Maximum EIRP(W)	Emission Designator (99%OBW)	Maximum EIRP(W)
1.4	1M08G7D	0.273	1M08W7D	0.236
3	2M69G7D	0.308	2M69W7D	0.268
5	4M48G7D	0.328	4M48W7D	0.279
10	8M95G7D	0.349	8M95W7D	0.307

LTE Band 12	and 12 QPSK		16QAM		
BW(MHz)	Emission Designator (99%OBW)	Maximum EIRP(W)	Emission Designator (99%OBW)	Maximum EIRP(W)	
1.4	1M08G7D	0.304	1M08W7D	0.253	
3	2M69G7D	0.298	2M69W7D	0.270	
5	4M48G7D	0.320	4M49W7D	0.236	
10	8M97G7D	0.324	8M98W7D	0.275	



LTI	E Band 17		QPSK			16QA	ort No.: TCT18080 M	
в	W(MHz)	Emission Designator (99%OBW)	Maxii	mum EIRP(W)	Emissio Designat (99%OBN	or	Maximum EIR	P(W)
	5	4M48G7D		0.482	4M48W7	'D	0.423	
	10	8M97G7D	- I.	0.491	8M98W7	Ď	0.434	

C RH mbar the EUT in continu- nodulation f 3m chamber. Measure the test, each emiss the test, each emiss l operating modes, re- worst position, mani- itenna height from 1m	urements in both sion was maximized otated about all 3 axis
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the test, each emiss Il operating modes, re worst position, mani	sion was maximized otated about all 3 axis
st-case are shown in	n to 4m in both
×.	9

escription Operatio			
Channel	2(1.4MHz) Frequency (MHz)	Channel	and 2(3MHz) Frequency (MHz
18607	1850.7	18615	1851.5
18900	1880	18900	1880
19193	1909.3	19185	1908.5
LTE Band 2(5MHz)			nd 2(10MHz)
Channel	Frequency (MHz)	Channel	Frequency (MHz
18625	1852.5	18650	1855
18900	1880	18900	1880
19175	1907.5	19150	1905
LTE Band 2(15MHz)		LTE Ba	nd 2(20MHz)
Channel	Frequency (MHz)	Channel	Frequency (MHz
18675	1857.5	18700	1860
18900	1880	18900	1880
19125	1902.5	19100	1900
No. 1)	
LTE Band 4(1.4MHz)		LTE Ba	and 4(3MHz)
Channel	Frequency (MHz)	Channel	Frequency (MHz
19957	1710.7	19965	1711.5
20175	1732.5	20175	1732.5
20393	1754.3	20385	1753.5
LTE Ban	d 4(5MHz)	LTE Ba	nd 4(10MHz)
Channel	Frequency (MHz)	Channel	Frequency (MHz
19975	1712.5	20000	1715
20175	1732.5	20175	1732.5
20375	1752.5	20350	1750
LTE Ban	d 4(15MHz)	LTE Ba	nd 4(20MHz)
Channel	Frequency (MHz)	Channel	Frequency (MHz
20025	1717.5	20050	1720
20175	1732.5	20175	1732.5
20325	1747.5	20300	1745

	Channel	Frequency (MHz)	Channel	Frequency (MHz)	
	20407	824.7	20415	825.5	
	20525	836.5	20525	836.5	
	20643	848.3	20635	847.5	
	LTE Band	5(5MHz)	LTE Band 5(10MHz)		
	Channel	Frequency (MHz)	Channel	Frequency (MHz)	
	20425	826.5	20450	829	
	20525	836.5	20525	836.5	
\mathcal{T}	20625	846.5	20600	844	

	LTE Band	12(1.4MHz)	LTE Band 12(3MHz)			
	Channel	Frequency (MHz)	Channel	Frequency (MHz)		
	23017	699.7	23025	700.5		
	23095	707.5	23095	707.5		
•)	23173	715.3	23165	714.5		
	LTE Band	12(5MHz)	LTE Band 12(10MHz)			
	Channel	Frequency (MHz)	Channel	Frequency (MHz)		
	23035	701.5	23060	704		
	23095 707.5 23155 713.5		23095	707.5		
			23130	711		

LTE Band	l 17(5MHz)	LTE Band 17(10MHz)			
Channel Frequency (MHz)		Channel	Frequency (MHz)		
23755	706.5	23780	709		
23790	710	23790	710		
23825	713.5	23800	711		

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LTE Band 5(3MHz)



LTE Band 5(1.4MHz)

4.2. Test Mode

All modes and data rates and positions were investigated. Test modes are chosen to be reported as the worst case configuration below:

Test Mode				
Band	Radiated TCs	Conducted TCs		
LTE Band 2	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)		
LTE Band 4	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)		
LTE Band 5	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz)		
LTE Band 12	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz)		
LTE Band 17	QPSK Link (5MHz / 10MHz)	16QAM Link (5MHz / 10MHz)		

Antenna port conducted and radiated test items were performed according to KDB 971168 D01 Power Meas License Digital Systems v03 with maximum output power. Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

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Report No.: TCT180806E042 Bandwidth (MHz) Modulation RB # Test Channel Test Items Band QPSK 1.4 3 5 10 15 20 16QAM 1 Half Full L М н 2 v v v v v v v v v v v v v v Max. Output 4 v v V v v v v v v v v v v v Power 5 v v v v v v -v v v v v v 12 v v v v v v v v v v v v -17 -v v _ v v v v v v v v 2 v v v v v v v v v v v v v v Peak-to-Average 4 v v v v v v v v v v v v v v Ratio 5 v v v v v v v v v v v v --12 v v v v _ _ v v v v v v v v 17 -_ v -v v v v v v v v v 26dB and 99% 2 v v v v v v v v v v v v v v Bandwidth 4 v v v v v v v v v v v v v v 5 v v v v 2 v v ۷ v v v v v 12 v v v -v v v v v v v v v 17 -v v -v v v v v v v v RB # Bandwidth (MHz) Modulation **Test Channel Test Items** Band 20 5 QPSK 1.4 3 10 15 16QAM 1 Half Full L Μ н 2 v v v v v v v v v v v v v Conducted 4 v v v v v v v v v v v v v Band Edge 5 v v v v v v v v v v v 12 v v ۷ v -v v v v v v v 17 _ v v v v v v --v v v _ 2 v v v v v v v v -_ v v v v Conducted 4 v v v v v v v v v v v v Spurious 5 v v v v Ļ v v v 1. v v v Emission 12 v v v v v v v -v v v 17 v v v v v v v v 2 2 v -. -v v v . v v v Frequency 4 1 _ -_ _ v v v v v v v Stability 5 -----v v v v v v v 2 12 v _ v v v v v v 17 v . 2 4 v 2 -. v v v v v -

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	CT			HNOLOGY	v	v		v			v	v v		<u>.: TCT18</u>		
E.R.F	./ E.I.R.P.	2	v	v v	v	v	v v	v	v v	v v	v	v	v	v v	v v	\ \ \
		5	v	v	v	v		\mathbf{S}	v	v	v	v	v	v	v	T,
		12	v	v	v	v	_	<u> </u>	v	v	v	v	v	v	v	,
		17	-	-	v	v	-	-	v	v	v	v	v	v	v	,
	diated	2	v	-		-	-	-	v	v	v	-	-	v	v	'
	ourious	4	v	-		/ -	-	-	v	V V	v	-	-	v	v	,
Er	nission	5	v	-	-	-	-	-	v	v	v	-	-	v	v	'
		12	v	-	-	-	-	-	v	v	v		-	v	v	
		17	(\mathbf{G})	-	v	-	-	5-)	v	v	v	<u>()</u>	-	v	v	,
	Note									chosen f supporte		ing)	

Report No.: TCT180806E042 4.3. Description of Support Units The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests. Model No. Serial No. FCC ID Trade Name Equipment Note: 1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test. 2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use. **Configuration of Tested System** 4.4. 120 Vac / 60 Hz EUT EUT (Adapter) (USB Cable) Dipole Antenna

4.5. Measurement Results Explanation Example

For all conducted test items:

The offset level is set in the spectrum analyzer to compensate the RF cable loss and attenuator factor between RF conducted output port and spectrum analyzer. With the offset compensation, the spectrum analyzer reading level will be exactly the RF output level. The spectrum analyzer offset is derived from RF cable loss and attenuator factor. Offset = RF cable loss + attenuator factor.

(Earphone)

System Simulator

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5. Facilities and Accreditations

5.1. Facilities

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 645098

Shenzhen Tongce Testing Lab.

The 3m Semi-anechoic chamber has been registered and fully described in a report with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files.

 IC - Registration No.: 10668A-1 The 3m Semi-anechoic chamber of Shenzhen TCT Testing Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing

5.2. Location

Shenzhen Tongce Testing Lab

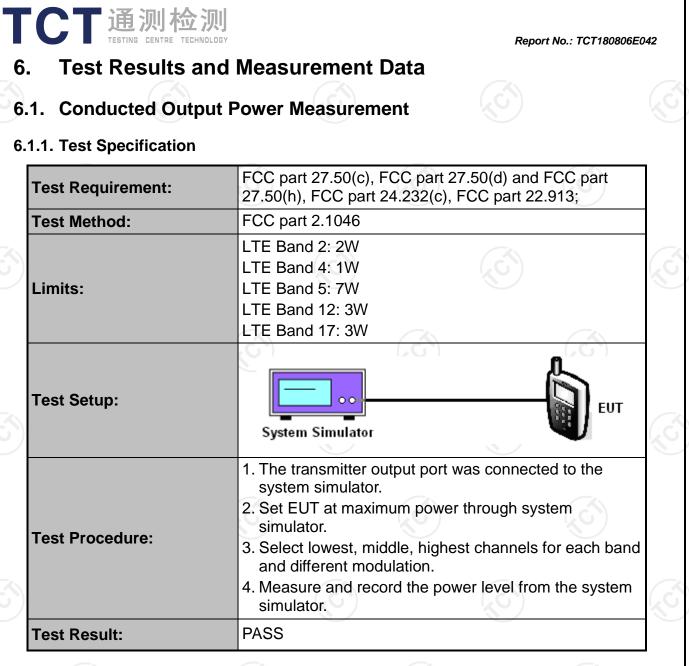
Address: 1B/F., Building 1, Yibaolai Industrial Park, Qiaotou, Fuyong, Baoan District, Shenzhen, Guangdong, China

TEL: +86-755-27673339

5.3. Measurement Uncertainty

The reported uncertainty of measurement $y \pm U$, where expended uncertainty U is based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of confidence of approximately 95 %.

No.	Item	MU	
1	Conducted Emission		
2	RF power, conducted	±0.12dB	
3	Spurious emissions, conducted	±0.11dB	
4	All emissions, radiated(<1G)	±3.92dB	
5	All emissions, radiated(>1G)	±4.28dB	
6	Temperature	±0.1°C	
7	Humidity	±1.0%	_



6.1.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Sep. 27, 2018
RF cable (9kHz-40GHz)	ТСТ	RE-05	N/A	Sep. 27, 2018
Antenna Connector	тст	RFC-02	N/A	Sep. 27, 2018

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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6.2. Peak to Average Ratio

6.2.1. Test Specification

Test Requirement:	FCC part 2.1046; 22.913; 24.232; 27.50(d); 27.50(c); 27.50(b)		
Test Method:	FCC KDB 971168 D01v03		
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.		
Test Setup:	System Simulator System Simulator EUT Spectrum Analyzer		
Test Procedure:	 The testing follows FCC KDB 971168 D01v03 Section 5.7.1. The EUT was connected to spectrum analyzer and system simulator via a power divider. Set EUT to transmit at maximum output power. Set the CCDF (Complementary Cumulative Distribution Function) option of the spectrum analyzer. Record the maximum PAPR level associated with a probability of 0.1%. 		
Test Result:	PASS		

6.2.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Sep. 27, 2018
Spectrum Analyzer	Agilent	N9020A	MY49100060	Sep. 27, 2018
RF cable (9kHz-40GHz)	тст	RE-05	N/A	Sep. 27, 2018
Antenna Connector	тст	RFC-02	N/A	Sep. 27, 2018

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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6.3. 99% Occupied Bandwidth and 26dB Bandwidth Measurement

6.3.1. Test Specification

Test Requirement:	FCC part 27.53(h)(3) and FCC part 27.53(m)(6), FCC part 24.238(b)
Test Method:	FCC part 2.1049
Limit:	N/A
Test Setup:	System Simulator Spectrum Analyzer
Test Procedure:	 The testing follows FCC KDB 971168 D01v03 Section 4.2. The EUT was connected to the spectrum analyzer and system simulator via a power divider. The RF output of the EUT was connected to the spectrum analyzer by RF cable and attenuator. The path loss was compensated to the results for each measurement. The 99% occupied bandwidth were measured, set RBW= 1% of OBW, VBW= 3*RBW, sample detector, trace maximum hold. The 26dB bandwidth were measured, set RBW= 1% of EBW, VBW= 3*RBW, peak detector, trace maximum hold.
Test Result:	PASS
X I	

6.3.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Sep. 27, 2018
Spectrum Analyzer	Agilent	N9020A	MY49100060	Sep. 27, 2018
RF cable (9kHz-40GHz)	тст	RE-05	N/A	Sep. 27, 2018
Antenna Connector	ТСТ	RFC-02	N/A	Sep. 27, 2018

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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4.1. Test Specification			
Test Requirement:	FCC part 27.53(h), FC FCC part 27.53(m)(4),	C part 27.53(g) , FCC part 24.238(a), 22.9	917(a)
Test Method:	FCC part2.1051		G)
Limit:	-13dBm		
Test Setup:	System Simulator	Power Divider	<u>(</u>)
Test Procedure:	 6.0. 2. The EUT was connersisted simulator vi 3. The RF output of EU analyzer by an RF on the path loss was one each measurement 4. The band edges of the highest RF powers 5. The conducted spurtility frequency range was 6. The RF fundamentation against the limit line 7. The limit line is derive the transmitter power P(Watts) = P(W) - [2000 (P)] (dBm) - [2000 (P)] (d	JT was connected to the s cable and attenuator. compensated to the resul ow and high channels for were measured. ious emission for the who as taken. I frequency should be exc in the operating frequent yed from 43 + 10log(P) dE	lyzer and spectrum ts for the ole cluded hcy band. 3 below
Test Result:	PASS		
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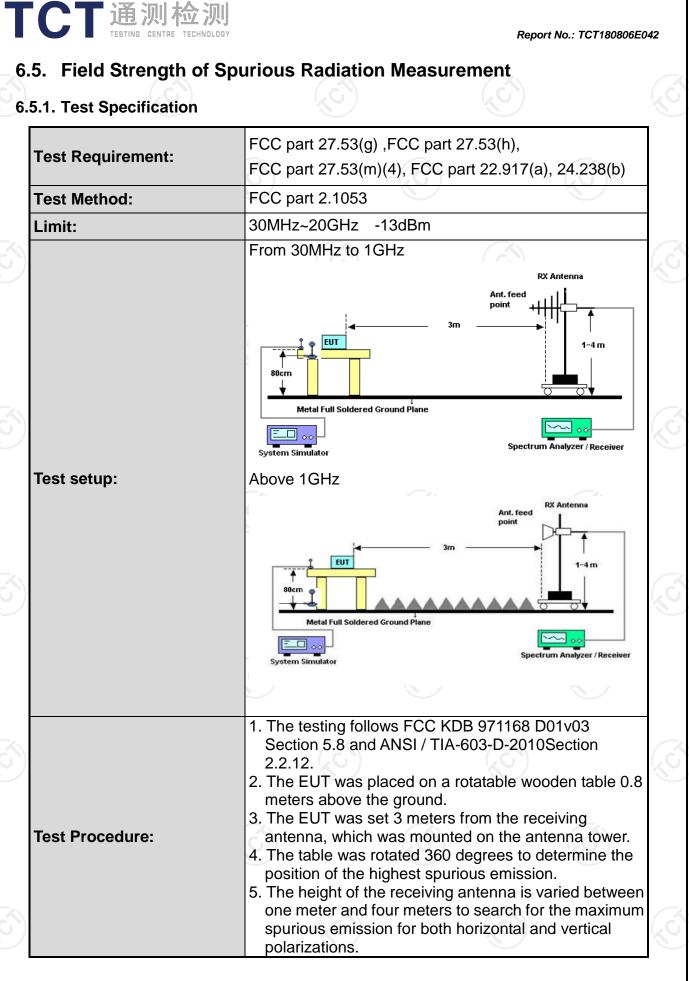
6.4.2. Test Instruments

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)	Equipment	Manufacturer	Model	Serial Number	Calibration Due
	Wideband Radio Communication Tester	R&S	CMW500	114220	Sep. 27, 2018
	Spectrum Analyzer	Agilent	N9020A	MY49100060	Sep. 27, 2018
	RF cable (9kHz-40GHz)	тст	RE-05	N/A	Sep. 27, 2018
)	Antenna Connector	тст	RFC-02	N/A	Sep. 27, 2018

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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3	 6. Make the measurement with the spectrum analyzer's RBW = 1MHz, VBW = 3MHz, taking record of maximum spurious emission. 7. A horn antenna was substituted in place of the EUT and was driven by a signal generator. 8. Tune the output power of signal generator to the same emission level with EUT maximum spurious 	
3	 emission. 9. Taking the record of output power at antenna port. 10. Repeat step 7 to step 8 for another polarization. 11. EIRP (dBm) = S.G. Power – Tx Cable Loss + Tx Antenna Gain 12. ERP (dBm) = EIRP - 2.15 13. The RF fundamental frequency should be excluded against the limit line in the operating frequency band. 	
3	 14. The limit line is derived from 43 + 10log(P) dB below the transmitter power P(Watts) = P(W) - [43 + 10log(P)] (dB) = [30 + 10log(P)] (dBm) - [43 + 10log(P)] (dB) = -13dBm. For Band 17, he limit line is derived from 55 + 10log(P) dB below the transmitter power 	
Test results:	PASS	

6.5.2. Test Instruments

5.2. Test Instrument	s						
Radiated Emission Test Site (966)							
Name of Equipment	Manufacturer	Model	Serial Number	Calibration Due			
System simulator	R&S	CMU200	111382	Sep. 27, 2018			
Spectrum Analyzer	ROHDE&SCHW ARZ	R&S	FSQ	Sep. 27, 2018			
Signal Generator	HP	83623B	3614A00396	Sep. 27, 2018			
Broadband Antenna	Schwarzbeck	VULB9163	340	Sep. 27, 2018			
Horn Antenna	Schwarzbeck	BBHA 9120D	631	Sep. 27, 2018			
Broadband Antenna	Schwarzbeck	VULB9163	412	Sep. 27, 2018			
Horn Antenna	Schwarzbeck	BBHA 9120D	1201	Sep. 27, 2018			
Horn Antenna	Schwarzbeck	BBH 9170	582	Sep. 27, 2018			
Dipole Antenna	тст	TCT-RF	N/A	Sep. 27, 2018			
Coax cable (9kHz-1GHz)	тст	RE-low-01	N/A	Sep. 27, 2018			
Coax cable	тст	RE-high-02	N/A	Sep. 27, 2018			

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	(9kHz-400						
	Coax ca (9kHz-1G		ТСТ	RE-low-03	N/A	Sep. 27, 2018	
Coax cable (9kHz-40GHz) Antenna Mast EMI Test Software			RE-High-04	N/A	Sep. 27, 2018		
			Mast	Keleto	CC-A-4M	N/A	N/A
		oftware	Shurple Technology	EZ-EMC	N/A	N/A	
No		ation interval o nal system un		struments is 12 mont	ths and the calibration	ons are traceable to	

6.6. Frequency Stability Measurement 6.6.1. Test Specification **Test Requirement:** FCC part 27.54, FCC part 22.355, 24.235 Test Method: FCC Part 2.1055 \pm 2.5 ppm Limit: Test Setup: Thermal Chambe **Test Procedures for Temperature Variation** 1. The testing follows FCC KDB 971168 D01v03 Section 9.0. 2. The EUT was set up in the thermal chamber and connected with the system simulator. 3. With power OFF, the temperature was decreased to -30°C and the EUT was stabilized before testing. Power was applied and the maximum change in frequency was recorded within one minute. 4. With power OFF, the temperature was raised in 10°C steps up to 50°C. The EUT was stabilized at each step for at least half an hour. Power was applied and Test Procedure: the maximum frequency change was recorded within one minute. **Test Procedures for Voltage Variation** 1. The testing follows FCC KDB 971168 D01v03 Section 9.0. 2. The EUT was placed in a temperature chamber at 25±5° C and connected with the system simulator. 3. The power supply voltage to the EUT was varied from BEP to 115% of the nominal value measured at the input to the EUT. 4. The variation in frequency was measured for the worst case. PASS Test Result:

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6.6.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due	
Wideband Radio Communication Tester	R&S	CMW500	114220	Sep. 27, 2018	
Programable tempratuce and humidity chamber	JQ	JQ-2000	N/A	Sep. 27, 2018	
DC power supply	Kingrang	KR3005K 30V/5A	N/A	Sep. 27, 2018	
RF cable (9kHz-40GHz)	тст	RE-04	N/A	Sep. 27, 2018	
Antenna Connector	TCT	RFC-03	N/A	Sep. 27, 2018	

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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